Erratum

On the characterization of surface VO_x-species by XPS: layered oxidic systems as model catalysts

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In Table 2 on page 83 there were two wrong values in the last line. The entire table is printed correctly below, with the values concerned in bold.

Table 2. V 2p_{3/2} peak deconvolution after reduction of samples in H₂

Sample	Temperature of reduction					
	573 K			723 K		
	E _B (V ⁺⁵) ^a	E _B (V ⁺³)	inten- sity ratio ^b	E _B (V ⁺⁵)	E _B (V ⁺³)	inten- sity ratio
VO _x /Au	516.3	514.9	0.9	517.0	515.3	2.5
VO _x /SiO ₂	517.0	515.6	0.3	517.8	515.5	0.7
VO _x /Al ₂ O ₃	517.1	515.9	0.4	517.0	515.5	1.6
VO _x /TiO ₂	518.5	515.8	4	518.3	515.6	4.5

^a in eV

^b ratio of peak areas I(V⁺³)/I(V⁺⁵), no sensitivity correction applied